

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10591664	FUKUOKA ET AL.
Examiner	Art Unit	
BRENITRA M LEE	4176	

SEARCHED

Class	Subclass	Date	Examiner
313	484, 500, 503, 505, 506, 507, 512, 584, 586, 631	2/10/2009	BML

SEARCH NOTES

Search Notes	Date	Examiner
Inspec, Inventor Name Search, IEEE Explore, Foreign Patent Search, East Search	2/10/2009	BML

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner

/BRENITRA M. LEE/
Examiner, Art Unit 4176